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Results of Search in US Patent Collection db for:

AN/" FemtoMetrix, Inc": 8 patents.

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PAT. NO.	Title
1 11,293,965	Wafer metrology technologies
2 11,199,507	Systems for parsing material properties from within SHG signals
3 11,150,287	Pump and probe type second harmonic generation metrology.
4 10,928,188	Surface sensing systems and methods for imaging a scanned surface of a sample via sum-frequency vibrational spectroscopy.
5 10,663,504	Field-biased second harmonic generation metrology.
6 10,613,131	Pump and probe type second harmonic generation metrology.
7 10,591,525	Wafer metrology technologies
8 10,551,325	Systems for parsing material properties from within SHG signals

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